Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
	SUYAMA, AKIHIKO	
Examiner	Art Unit	
VAN T. PHAM	2627	

SEARCHED					
Class	Subclass	Date	Examiner		
		:			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
-	<u> </u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB) 369, 347 (text search only see search history printout).	8/23/2006	VP		
Consulted Wayne Young.	8/23/2006	VP		
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